



[40103/00501]

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s) : James HARRISON et al.
Serial No. : 10/033,975
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For : METHOD AND APPARATUS FOR WAFER-LEVEL
TESTING OF SEMICONDUCTOR LASER
Group Art Unit: : 2877
Examiner : Pham, Hoa Q.

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CHANGE OF CORRESPONDENCE ADDRESS

S I R:

As attorney of record, please amend the above-identified application to reflect our new correspondence address and telephone information:

Customer No. 30636
Fay Kaplun & Marcin, LLP
150 Broadway, Suite 702
New York, NY 10038
Tel: 212-619-6000
Fax: 212-619-0276

Respectfully submitted,

Dated: June 2, 2004

By: 
Patrick J. Fay, Reg. No. 35,508

Fay Kaplun & Marcin, LLP
150 Broadway, 7th Floor, Suite 702
New York, NY 10038
Tel: (212) 619-6000
Fax: (212) 619-0276